

Date Created : 2009/05/21
Date Issued On : 2009/07/08
PCN# : Q2092103

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Implementation of change:
Expected 1st Device Shipment Date: 2009/10/18

Earliest Year/Work Week of Changed Product: 0943

Change Type Description: Alternate Fab Location

Description of Change (From): Standard Discrete products fabricated by Tianjin wafer foundry.

Description of Change (To): Standard Discrete products fabricated by Li-Je wafer foundry

Reason for Change : Closure of the Tianjin wafer foundry.

Qual/REL Plan Numbers : Q20090313

Qualification :

The result show pass and no fail found

Results/Discussion for Qual Plan Number Q20090313

Test: (Autoclave) Conditions: 100%RH, 121C Standard: JESD22-A102					
Lot	Device	96-HOURS	Failure Code		
Q20090313AAACLVA	ES1A	0/77			
Q20090313BAACLVA	ES2D	0/77			
Q20090313CAACLVA	ES3J	0/77			
Q20090313DAACLVA	FEP16JT	0/77			
Q20090313EAACLVA	FES16CT	0/77			

Test: (High Humidity, High Temp, Rev. Bias) Conditions: 85%RH, 85C, 80% of Rated BV,max=100V Standard: JESD22-A101B					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090313AAH3TRBA	ES1A	0/77			
			0/77		

				0/77	
Q20090313BAH3TRBA	ES2D	0/77			
			0/77		
				0/77	
Q20090313CAH3TRBA	ES3J	0/77			
			0/77		
				0/77	
Q20090313DAH3TRBA	FEP16JT	0/77			
			0/77		
				0/77	
Q20090313EAH3TRBA	FES16CT	0/77			
			0/77		
				0/77	

Test: (High Temperature Reverse Bias) | Conditions: 150C, 80% Rated BV | Standard: JESD22-A108

Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090313AAHTRBA	ES1A	0/77			
			0/77		
				0/77	
Q20090313BAHTRBA	ES2D	0/77			
			0/77		
				0/77	
Q20090313CAHTRBA	ES3J	0/77			
			0/77		
				0/77	
Q20090313DAHTRBA	FEP16JT	0/77			
			0/77		
				0/77	
Q20090313EAHTRBA	FES16CT	0/77			
			0/77		
				0/77	

Test: (Power Cycle) | Conditions: Delta 100C, 2 min on2min off | Standard: MIL-STD-750-1036

Lot	Device	1000-CYCLES	5000-CYCLES	Failure Code
Q20090313AAPRCLA	ES1A	0/77		
Q20090313AAPRCLA	ES1A		0/77	
Q20090313BAPRCLA	ES2D	0/77		
Q20090313BAPRCLA	ES2D		0/77	
Q20090313CAPRCLA	ES3J	0/77		
Q20090313CAPRCLA	ES3J		0/77	
Q20090313DAPRCLA	FEP16JT	0/77		
Q20090313DAPRCLA	FEP16JT		0/77	
Q20090313EAPRCLA	FES16CT	0/77		
Q20090313EAPRCLA	FES16CT		0/77	

Test: (Precondition) | Conditions: | Standard: JESD22-A113

Lot	Device	Results	Failure Code
Q20090313AAPCNL1AA	ES1A	0/308	
Q20090313BAPCNL1AA	ES2D	0/308	
Q20090313CAPCNL1AA	ES3J	0/308	

Test: (Temperature Cycle) | Conditions: -55C, 150C | Standard: JESD22-A104

Lot	Device	100-CYCLES	500-CYCLES	1000	Failure Code
Q20090313AATMCL3A	ES1A	0/77			
			0/77		
				0/77	
Q20090313BATMCL3A	ES2D	0/77			
			0/77		
				0/77	
Q20090313CATMCL3A	ES3J	0/77			
			0/77		
				0/77	
Q20090313DATMCL3A	FEP16JT	0/77			
			0/77		
				0/77	
Q20090313EATMCL3A	FES16CT	0/77			
			0/77		
				0/77	

Product Id Description :

Affected FSIDs :

ES1A	ES1B	ES1C
ES1D	ES1F	ES1G
ES1H	ES1J	ES2A
ES2B	ES2C	ES2D
ES3A	ES3B	ES3C
ES3D	ES3J	FEP16ATA
FEP16ATD	FEP16AT	FEP16BTA
FEP16BTD	FEP16BT	FEP16CTA
FEP16CTD	FEP16CT	FEP16DTA
FEP16DTD	FEP16DT	FEP16FTD
FEP16FT	FEP16GTA	FEP16GTD
FEP16GT	FEP16HTD	FEP16HT
FEP16JTA	FEP16JTD	FEP16JT
FES16ATR	FES16AT	FES16BT
FES16CT	FES16DTR	FES16DT
FES16FT	FES16GT	FES16HT
FES16JTR		